

May 2002 Revised October 2006

# FSTU32X384 20-Bit Low Power Bus Switch with –2V Undershoot Protection

#### **General Description**

The Fairchild Switch FSTU32X384 provides 20 bits of high-speed CMOS TTL-compatible bus switches. The low On Resistance of the switch allows inputs to be connected to outputs without adding propagation delay or generating additional ground bounce noise. The device is organized as four 5-bit switches with separate bus enable  $(\overline{OE})$  signals. When  $\overline{OE}$  is LOW, the switch is ON and Port A is connected to Port B. When  $\overline{OE}$  is HIGH, the switch is OPEN and a high-impedance state exists between the two ports.

The A and B Ports are protected against undershoot to support an extended range to 2.0V below ground. Fairchild's integrated Undershoot Hardened Circuit (UHC®) senses undershoot at the I/O and responds by preventing voltage differentials from developing and turning the switch on.

#### **Features**

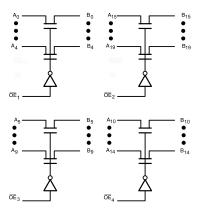
- $\blacksquare$  4 $\Omega$  switch connection between two ports
- Minimal propagation delay through the switch
- $\blacksquare$  Ultra low power with < 0.1  $\mu A$  typical  $I_{CC}$
- Zero ground bounce in flow-through mode
- Control inputs compatible with TTL level
- See Application Note AN-5008 for details on FSTU Undershoot Protected Fairchild Switch Family

#### **Ordering Code:**

Order Number	Package Number	Package Description
FSTU32X384QSP	MQA48A	48-Lead Quarter Size Very Small Outline Package (QVSOP), JEDEC MO-154, 0.150" Wide

Device also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code.

#### **Logic Diagram**



UHC® is a registered trademark of Fairchild Semiconductor Corporation.

© 2002 Fairchild Semiconductor Corporation

DS500705

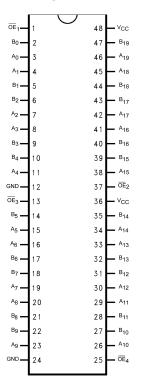
## **Pin Descriptions**

Pin Names	Description		
$\overline{\sf OE}_{\sf X}$	Bus Switch Enable		
А	Bus A		
В	Bus B		

#### **Truth Table**

Inputs	Inputs/Outputs				
$\overline{OE}_X$	A, B				
L	A = B				
Н	Z				

### **Connection Diagram**



#### **Absolute Maximum Ratings**(Note 1)

# Recommended Operating Conditions (Note 3)

 $\begin{array}{ll} \mbox{Power Supply Operating (V$_{CC}$)} & 4.0 \mbox{V to } 5.5 \mbox{V} \\ \mbox{Input Voltage (V$_{IN}$)} & 0 \mbox{V to } 5.5 \mbox{V} \\ \mbox{Output Voltage (V$_{OUT}$)} & 0 \mbox{V to } 5.5 \mbox{V} \\ \end{array}$ 

Input Rise and Fall Time  $(t_r, t_f)$ 

Note 1: The "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the "Electrical Characteristics" table are not guaranteed at the absolute maximum ratings. The "Recommended Operating Conditions" table will define the conditions for actual device operation.

Note 2: The input and output negative voltage ratings may be exceeded if the input and output diode current ratings are observed.

Note 3: Unused control inputs must be held HIGH or LOW. They may not float

#### **DC Electrical Characteristics**

		V <sub>CC</sub>	$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$					
Symbol	Parameter	(V)	Min	Min Typ (Note 4)		Units	Condition	
V <sub>IK</sub>	Clamp Diode Voltage	4.5			-1.2	V	I <sub>IN</sub> = – 18mA	
V <sub>IH</sub>	HIGH Level Input Voltage	4.0 - 5.5	2.0			V		
V <sub>IL</sub>	LOW Level Input Voltage	4.0 - 5.5			0.8	V		
I	Input Leakage Current	5.5			±1.0	μА	0 ≤ V <sub>IN</sub> ≤ 5.5V	
		0			10	μΛ	V <sub>IN</sub> = 5.5V	
I <sub>OZ</sub>	OFF-STATE Leakage Current	5.5			±1.0	μΑ	0 ≤ A, B ≤ V <sub>CC</sub>	
R <sub>ON</sub>	Switch On Resistance	4.5		4	7		V <sub>IN</sub> = 0V, I <sub>IN</sub> = 64 mA	
	(Note 5)	4.5		4	7	Ω	V <sub>IN</sub> = 0V, I <sub>IN</sub> = 30 mA	
		4.5		8	15	1 12	V <sub>IN</sub> = 2.4V, I <sub>IN</sub> = 15 mA	
		4.0		11	20	1	V <sub>IN</sub> = 2.4V, I <sub>IN</sub> = 15 mA	
Icc	Quiescent Supply Current (Note 6)	5.5			3	μΑ	$V_{IN} = V_{CC}$ or GND, $I_{OUT} = 0$	
ΔI <sub>CC</sub>	Increase in I <sub>CC</sub> per Input	5.5			2.5	mA	One Input at 3.4V	
	(Note 7)						Other Inputs at V <sub>CC</sub> or GND	
V <sub>IKU</sub>	Voltage Undershoot	5.5			-2.0	V	$\frac{0.0 \text{ mA} \ge I_{\text{IN}} \ge 50 \text{ mA}}{\text{OE}} = 5.5 \text{V}$	

Note 4: All typical values are at V<sub>CC</sub> = 5.0V, T<sub>A</sub> = 25°C.

Note 5: Measured by voltage drop between A and B pin at indicated current through the switch. On Resistance is determined by the lower of the voltages on the two (A or B) pins.

Note 6: Per  $V_{\rm CC}$  pin.

Note 7: Per TTL driven input, control pins only.

#### **AC Electrical Characteristics**

Symbol	Parameter	$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$ $C_L = 50 \text{ pF, RU} = \text{RD} = 500\Omega$				Units	Conditions	Figure Number
- Cyllibol	i arameter	$V_{CC} = 4.5 - 5.5V$		V <sub>CC</sub> = 4.0V		Oilles		
		Min	Max	Min	Max			
t <sub>PHL</sub> , t <sub>PLH</sub>	Propagation Delay Bus to Bus (Note 8)		0.25		0.25	ns	V <sub>I</sub> = OPEN	Figures 2, 3
t <sub>PZH</sub> , t <sub>PZL</sub>	Output Enable Time $\overline{OE}_1$ , $\overline{OE}_2$ to $A_n$ , $B_n$	1.0	5.7		6.2	ns	$V_I = 7V$ for $t_{PZL}$ $V_I = OPEN$ for $t_{PZH}$	Figures 2, 3
t <sub>PHZ</sub> , t <sub>PLZ</sub>	Output Disable Time $\overline{OE}_1$ , $\overline{OE}_2$ to $A_n$ , $B_n$	1.5	5.2		5.5	ns	$I_I = 7V$ for $t_{PLZ}$ $V_I = OPEN$ for $t_{PHZ}$	Figures 2, 3

Note 8: This parameter is guaranteed by design but not tested. The bus switch contributes no propagation delay other than the RC delay of the typical On Resistance of the switch and the 50pF load capacitance, when driven by an ideal voltage the source (zero output impedance).

#### Capacitance (Note 9)

Symbol Parameter		Тур	Max	Units	Conditions
C <sub>IN</sub> Control Input Capacitance		3	6	pF	$V_{CC} = 5.0V$
C <sub>I/O</sub> (OFF) Input/Output Capacitance		5	13	pF	$V_{CC}$ , $\overline{OE} = 5.0V$

Note 9: Capacitance is characterized but not tested.

#### **Undershoot Characteristic** (Note 10)

Symbol	Parameter	Min	Тур	Max	Units	Conditions
V <sub>OUTU</sub>	Output Voltage During Undershoot	2.5	V <sub>OH</sub> - 0.3		V	Figure 1

Note 10: This test is intended to characterize the device's protective capabilities by maintaining output signal integrity during an input transient voltage undershoot event.

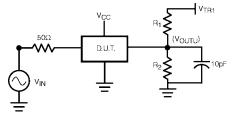
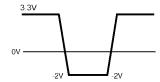


FIGURE 1.

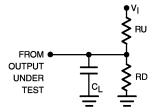
#### **Device Test Conditions**

Parameter	Value	Units		
V <sub>IN</sub>	see Waveform	V		
$R_1 = R_2$	100K	Ω		
$V_{TRI}$	11.0	V		
V <sub>CC</sub>	5.5	V		

# Transient Input Voltage (V<sub>IN</sub>) Waveform



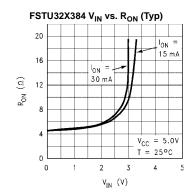
# AC Loading and Waveforms

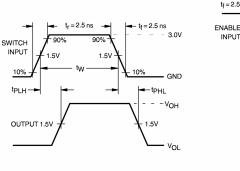


Note: Input driven by 50  $\Omega$  source terminated in 50  $\Omega$  Note: C\_L includes load and stray capacitance

Note: Input PRR = 1.0 MHz,  $t_W$  = 500 ns

#### FIGURE 2. AC Test Circuit





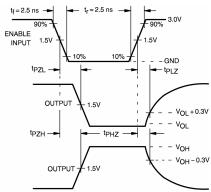
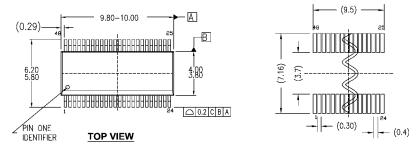
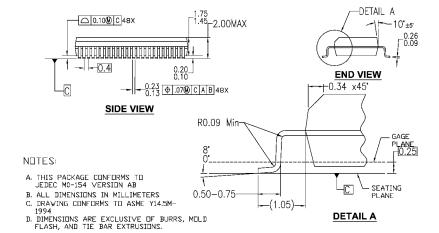


FIGURE 3. AC Waveforms

### Physical Dimensions inches (millimeters) unless otherwise noted



# LAND PATTERN RECOMMENDATION



MQA48AREVA

48-Lead Quarter Size Very Small Outline Package (QVSOP), JEDEC MO-154, 0.150" Wide Package Number MQA48A

#### **Technology Description**

The Fairchild Switch family derives from and embodies Fairchild's proven switch technology used for several years in its 74LVX3L384 (FSTU32X384) bus switch product.

Fairchild does not assume any responsibility for use of any circuitry described, no circuit patent licenses are implied and Fairchild reserves the right at any time without notice to change said circuitry and specifications.

#### LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF THE PRESIDENT OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury to the user.
- A critical component in any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

www.fairchildsemi.com